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	Application No.	Applicant(s)
Nation of Allowahility	10/734,676	OGIHARA ET AL.
Notice of Allowability	Examiner	Art Unit
	Stephen W. Smoot	2813
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communication IGHTS. This application is subject t	pplication. If not included n will be mailed in due course. THIS
1. 🔀 This communication is responsive to applicant's amendment	ent filed on 21 June 2006.	
2. X The allowed claim(s) is/are 10, 13-15, 18-19, 27-38.		
3. ☑ Acknowledgment is made of a claim for foreign priority un a) ☑ All b) ☐ Some* c) ☐ None of the:		
1. Certified copies of the priority documents have been received.		
2. Certified copies of the priority documents have been received in Application No		
3. Copies of the certified copies of the priority documents have been received in this national stage application from the		
International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give		
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.		
(a) I including changes required by the Notice of Draftspers	son's Patent Drawing Review (PTO	-948) attached
1) hereto or 2) to Paper No./Mail Date	:	
(b) including changes required by the attached Examiner' Paper No./Mail Date	s Amendment / Comment or in the 0	Office action of
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t	.84(c)) should be written on the drawi he header according to 37 CFR 1.121	ngs in the front (not the back) of (d).
6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.		
Attachment(s)	5 🗆 Notice of Informal 6	Patent Application (PTO-152)
 Notice of References Cited (PTO-892) Notice of Draftperson's Patent Drawing Review (PTO-948) 	6. 🔲 Interview Summary	(PTO-413),
3. Information Disclosure Statements (PTO-1449 or PTO/SB/0	Paper No./Mail Da D8), 7. ⊠ Examiner's Amend	nte ment/Comment
Paper No./Mail Date 4. Examiner's Comment Regarding Requirement for Deposit of Biological Material		ent of Reasons for Allowance
	9. Other	
Stor Ren W	Smoot	Stephen W. Smoot Patent Examiner Art Unit 2813

Application/Control Number: 10/734,676 Page 2

Art Unit: 2813

This Office action is in response to applicant's amendment filed on 21 June 2006.

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Nick Bromer on 31 July 2006.

2. The application has been amended as follows:

In the Claims:

In claim 15, line 5, change "said first interdielectric layer" to --a first interdielectric layer disposed between said substrate and said adhesion layer--.

- 3. Claims 10, 13-15, 18-19, 27-38 are allowed.
- 4. The following is an examiner's statement of reasons for allowance:

- Claims 10, 13-15 are allowed because the prior art of record does not teach or suggest, in combination with the other claim limitations, a semiconductor structure that includes an adhesion layer mainly consisting of semiconductor material disposed on a substrate and a semiconductor thin film bonded on the adhesion layer, further comprising an interconnecting layer for electrically connecting a semiconductor device that corresponds to the semiconductor thin film to an integrated circuit that corresponds to the substrate, wherein an interdielectric layer electrically isolates the interconnecting layer from the semiconductor thin film and a part of the substrate;
- Claim 19 is allowed because the prior art of record does not teach or suggest, in combination with the other claim limitations, a semiconductor structure that includes an adhesion layer mainly consisting of semiconductor material disposed on a substrate and a semiconductor thin film bonded on the adhesion layer, wherein a plurality of semiconductor thin films are arranged on the adhesion layer at regular intervals; and
- Claims 18, 27-38 are allowed because the prior art of record does not teach or suggest, in combination with the other claim limitations, a semiconductor structure that includes an adhesion layer mainly consisting of semiconductor material disposed on a substrate and a semiconductor thin film bonded on the adhesion layer, wherein a main constituent of the adhesion layer is different from a main constituent of the semiconductor thin film, wherein the semiconductor material has an affinity to both the semiconductor thin film and the substrate and

Application/Control Number: 10/734,676 Page 4

Art Unit: 2813

wherein the semiconductor thin film includes at least one semiconductor device that is any of a light emitting element, a light sensing element, a Hall element, or a piezoelectric element.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Stephen W. Smoot whose telephone number is 571-272-1698. The examiner can normally be reached on M-F (8:00 am to 4:30 pm).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl Whitehead, Jr. can be reached on 571-272-1702. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/734,676

Art Unit: 2813

Page 5

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

SWS